

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1	(light\$3 and (measurement\$3 or calculat\$3 or computation) and imag\$3 and illuminat\$4 and register\$3 and reference and model\$3 and transformation and estimat\$3 and (detect\$4 or identif\$3 or recogni\$4) and gauge).CLM.	US-PGPU B	AND	ON	2007/09/27 16:07

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1	(light\$3 and (measurement\$3 or calculat\$3 or computation) and imag\$3 and illuminat\$4 and register\$3 and reference and model\$3 and transformation and estimat\$3 and (detect\$4 or identif\$3 or recogni\$4) and gauge).CLM.	US-PGPU B	AND	ON	2007/09/27 16:16
L3	3844	((382/106,152,154) or (356/602,603,604,612,614)).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2007/09/27 16:18
L4	0	1 and (light\$3 or illuminat\$4) and imag\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:27
L5	2542	3 and (light\$3 or illuminat\$4) and imag\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:19

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L6	29	5 and gauge near4 measurement\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:21
L7	29	6 and (measurement\$3 or calculat\$3 or computation)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:26
L8	1	7 and register\$3 and reference and model\$3 and transformation and estimat\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:27
L9	10777	gauge near4 measurement\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:26

EAST Search History

L10	11	9 and register\$3 and reference and model\$3 and transformation and estimat\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:21
L11	8	10 and (light\$3 or illuminat\$4) and imag\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:21
L12	5	11 and module and (measurement\$3 or calculat\$3 or computation)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:28
L13	1	9 and known near3 reference near4 model\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:24

EAST Search History

L14	51	9 and reference near4 model\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:24
L15	13	14 and register\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:25
L16	5	15 and transformation	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:25
L17	4444	non-contact near3 measurement\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:26

EAST Search History

L18	125	17 and gauge near4 measurement\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:28
L19	125	18 and (measurement\$3 or calculat\$3 or computation)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:26
L20	63	19 and (light\$3 or illuminat\$4) and imag\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:27
L21	2	20 and register\$3 and reference and model\$3 and transformation and estimat\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:27

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L22	16	17 and register\$3 and reference and model\$3 and transformation and estimat\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:27
L23	14	22 and (light\$3 or illuminat\$4) and imag\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:28
L24	9	23 and module and (measurement\$3 or calculat\$3 or computation)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:28
L25	2	24 and gauge near4 measurement\$3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/09/27 16:28

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» Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

[Select All](#) [Deselect All](#)**1. Multi-scale phase-based local features**Carneiro, G.; Jepson, A.D.;
[Computer Vision and Pattern Recognition, 2003. Proceedings. 2003 IEEE Conference on](#)

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